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MOLECULAR ALIGNMENT OF NEUTRAL AND p-DOPED HEAD-TO-TAIL TYPE POLY(3-HEXYLTHIOPHENE-2,5-DIYL) AND n-ALKANES ON THE SURFACE OF SUBSTRATES

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Neutral and p-doped head-to-tail poly(3-hexylthiophene-2,5-diyl), HT-P3HexTh, as well as n-alkane (e.g., triacontane and nonacosane) are aligned with the alkyl chain oriented toward the surface of substrates such as platinum plate and silicon plate. XRD data support the alignment.

Keywords: molecular alignment; poly(3-hexylthiophene-2,5-diyl); n-alkane

INTRODUCTION

The perpendicular [1–3a] and parallel [3,4] alignment of π -conjugated polymers on the surface of substrates such as carbon sheets and glass plates has been a subject of recent interest. We now report molecular alignment of neutral and p-doped head-to-tail type poly(3-hexylthiophene-2,5-diyl) [5–7], HT-P3HexTh, prepared via an organometallic route.

HT-P3HexTh (R = hexyl) proportion of the HT unit: 98.5%. Number average molecular weight (Mn) = 24000.

In order to reveal the inclination of the alkyl chain for ordering on the surface of substrates, we have also investigated molecular alignment of the following n-alkanes on the surface of substrates.

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$$CH_3(CH_2)_nCH_3$$
 $n = 28$ (triacontane)
27 (nonacosane)
22 (tetracosane)

Recently, it was reported that a thin film of HT-P3HexTh showed superconductivity when the film was placed in a field-effect-transistor (FET) geometry and doped electrically [8,9]. For the superconductivity, importance of molecule alignment of HT-P3HexTh [10, 11] was proposed [8,9].

RESULTS AND DISCUSSION

Curve (a) in Figure 1 shows the XRD pattern of an as-cast film of HT-P3HexTh (proportion of the HT unit = 98.5%, as evaluated from ¹H NMR data [5-7]) on a Pt plate. The XRD pattern was measured with a RINT2100 Ultima+/PC X-ray diffractometer. The film was cast from a CHCl₃ solution of HT-P3HexTh (6.7 gdm⁻³), and CHCl₃ was removed by natural evaporation. As shown in Figure 1, the curve (a) shows 3 peaks at 16.2 Å/n (n=1-3). The distance d_1 of 16.2 Å has been assigned to a distance between polythiophene chains separated by the hexyl groups [5–7, 11]. The as-cast film of HT-P3HexTh does not show a d_2 peak assigned to a face-to-face packing distance between polythiophene planes (cf. Figure 2) [5–7, 11], although this d_2 peak is clearly observed after the film is peeled from the surface and crushed (cf. curve (b) in Figure 1). These results indicate that HT-P3HexTh molecules are aligned with the hexyl groups oriented toward the surface of the Pt substrate, as depicted in Figure 2. Ascast films of HT-P3HexTh on glass, gold, crystalline Al₂O₃, and Teflon substrates give XRD patterns (e.g., curve (c) in Figure 1 for the glass substrate) similar to that of the as-cast film of HT-P3HexTh on the Pt plate, revealing that the molecular alignment of HT-P3HexTh also takes place on the substrates. Similar alignment of HT-P3HexTh molecules on glass and SiO₂/Si substrates has previously been reported [6, 10, 11], and the present results indicate such molecular alignment can take place on various kinds of substrates.

HT-P3HexTh can be electrochemically deposited on various metal electrodes [13], similar to electron-donating compounds such as tetrathiafulvalene and its derivatives.

$$\begin{array}{c} C_6H_{13} & \text{electrochemical} \\ \text{deposition on anode} \\ \hline S & n & [N(n\text{-}C_4H_9)_4]BF_4/\text{ THF} \\ \text{polymer in} \\ \text{solution} & Pt \text{ electrode} \\ \end{array} \begin{array}{c} C_6H_{13} \\ \\ \times x \text{ BF}_4 \\ \\ \text{n} \\ \text{p-doped polymer film} \\ \text{deposited on the Pt electrode} \\ \end{array}$$

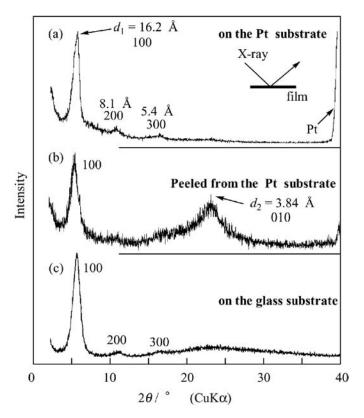


FIGURE 1 (a) XRD pattern of an as-cast film of HT-P3HexTh on a Pt plate. After the film is peeled from the Pt plate and crushed, it exhibits curve (b) which shows a 010 diffraction peak at $d_2 = 3.84\,\text{Å}$. (c) XRD pattern of an as-cast film of HT-P3HexTh on a glass substrate. For curves (a) and (c), X-ray was irradiated from the out-of-plane direction as depicted in Figure 1(a). The XRD pattern was measured with a symmetrical-reflection technique.

The electrochemically deposited film of HT-P3HexTh is in a p-doped (or oxidized) state. Curves (a) and (b) in Figure 3 exhibit XRD patterns of the as-grown, electrochemically deposited films of HT-P3HexTh. XRD patterns of two samples obtained at different current densities are exhibited.

The complete absence of the 010 (or d_2) peak in the curves (a) and (b) in Figure 3 indicates that the electrochemically deposited p-doped HT-P3HexTh molecules are also aligned in a manner similar to that depicted in Figure 2. A somewhat longer d_1 value of the p-doped HT-P3HexTh than that of nondoped HT-P3HexTh may be due to the incorporation of the BF₄⁻ dopant. When the electrochemically deposited film is peeled from the Pt

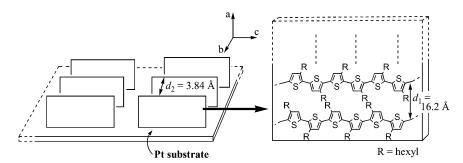


FIGURE 2 Alignment of HT-P3HexTh molecules on the surface of the substrate.

electrode and crushed, it exhibits a curve (c) which shows a 010 (or d_2) diffraction peak.

In order to investigate the tendency for the alkyl chain to be ordered on the surface of substrates, we have investigated alignment of n-alkanes on the surface of substrates. Curve (a) in Figure 4 shows an XRD pattern of powdery triacontane. This XRD pattern agrees with reported data [14]. Triacontane reportedly forms a monoclinic crystal with the dimensions of $a=5.581\,\text{Å}$, $b=7.445\,\text{Å}$, c (the direction of the alkyl chain) = 40.71 Å, and $\beta=118.95^\circ$ as depicted in the inset in Figure 4(a).

Curves (b), (c), and (d) in Figure 4 show XRD patterns of triacontane film (0.1 µm) obtained by casting from a CHCl₃ solution (8.5 gdm⁻³) on a Si zero background sample plate, Pt plate, and glass plate, respectively. Strong remaining 00n diffraction peaks at d=35.6 Å/n [14] (n = 1–15) in the XRD pattern film and considerable weakening of other peaks, especially weakening of the 110 peak, indicate that the long n-alkane (triacontane) itself has a strong tendency to be aligned essentially perpendicular to or with the angle of $\beta=118.95^{\circ}$ toward the surface of the substrate.

Nonacosane and tetracosane form somewhat different types of crystals—orthorhombic and triclinic crystals, respectively [14]. However, both the long n-alkane molecules are also aligned in the cast film, similar to the case of triacontane. For example, strong remaining 00n ($n=2,4,6,\ldots$) diffraction peaks in the XRD curve (e) in Figure 4 support the view that nonacosane molecules are also aligned with the alkane chain directed toward the surface of the substrate. The cast film of tetracosane gives strong peaks at $d=30.3\,\text{Å/n}$ [14] ($n=1,2,3,\ldots$), which also agrees with a similar alignment.

As described above, alkanes themselves have nature to be aligned on the surface of the substrate, and the molecular alignment of HT-P3HexTh on the surface of the substrates seems based on the inclination of the hexyl chain to be aligned toward the surface of the substrate. The side hexyl

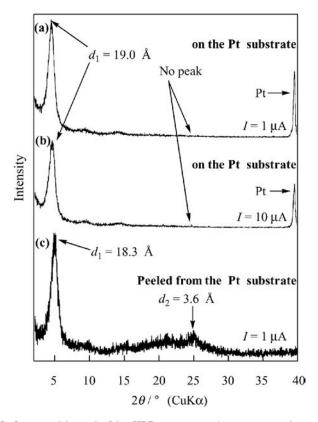


FIGURE 3 Curves (a) and (b): XRD pattern of as-grown, electrochemically deposited film of p-doped HT-P3HexTh. The electrochemical deposition was carried out at a galvanostatic mode on a Pt plate $(1 \text{ cm} \times 2 \text{ cm})$ immersed in a THF solution containing HT-P3HexTh (saturated: about 2 gdm^{-3} [7]) and $[N(n\text{-}C_4H_9)_4]BF_4$ (3.29 gdm⁻³) at room temperature; (a) at $1 \mu A$ for 5 h; (b) at $10 \mu A$ for 3 h. The former and latter films had thickness of $4 \mu m$ and $3 \mu m$, respectively, as measured with a Dektak³ ST Surface Profiler. XPS analysis of S and B indicates that the sample for the XRD curve (a) is formulated as $(C_{10}H_{14}S\cdot0.008\ BF_4)_n$. When the film used for the measurement of XRD curve (a) is peeled from the Pt plate and crushed, it exhibits curve (c), which shows a 010 diffraction peak. For (a) and (b), X-ray was irradiated as described in the caption of Figure 1.

chains in HT-P3HexTh are considered to take a well-packed structure [5-7]; consequently, the local molecular packing mode of the hexyl side chain is considered to be similar to the packing mode of n-alkane.

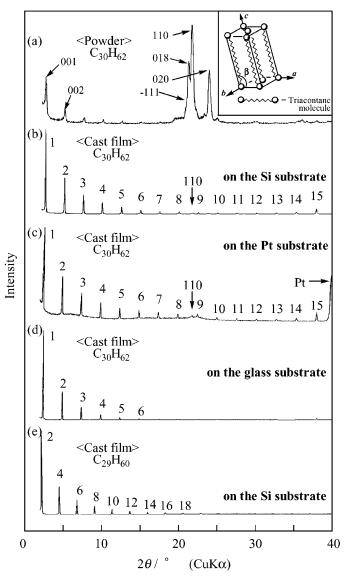


FIGURE 4 XRD patterns of (a) a powder of triacontane, (b) cast film of triacontane on a Si plate, (c) cast film of triacontane on a Pt plate, and (d) cast film of triacontane on a glass plate. The -111 diffraction peak of triacontane [14] appears as a shoulder peak in the curve (a). The numbers 1 through 15 in curves (b), (c), and (d) refer to the corresponding 00n peaks. Curve (e) exhibits the XRD pattern of cast film of nonacosane on a Pt plate. For curves (b)–(e), X-ray was irradiated from the out-of-plane direction, and the XRD pattern was measured with a symmetrical-reflection technique. Thickness of the films of n-alkanes = $0.10 \, \mu m$.

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- [14] Heyding, R. D., Russell, K. E., & Varty, T. L. (1990). Powder Diffr., 5, 93–100. The d values for 001 peaks of triacontane and tetracosane are 35.6 Å and 30.6 Å, respectively, which, in an experimental error, agree with the data observed in the present experiments.